Search Notes

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Application/Control No.	Applicant(s)/Patent Under Reexamination
10737339	FANG ET AL.
Examiner	Art Unit
Haile, Awet A	2616

SEARCHED				
Class	Subclass	Date	Examiner	
370	208	4/7/2008	Awet Haile	
370	210	4/7/2008	Awet Haile	
370	479	4/7/2008	Awet Haile	
370	260	4/7/2008	Awet Haile	
370	281	4/7/2008	Awet Haile	
370	392	14/7/2008	Awet Haile	
370	393	4/7/2008	Awet Haile	
370	474	4/7/2008	Awet Haile	
370	475	4/7/2008	Awet Haile	
370	476	4/7/2008	Awet Haile	
370	480	4/7/2008	Awet Haile	

SEARCH NOTES				
Search Notes	Date	Examiner		
East search	4/14/2008	Awet Haile		

INTERFERENCE SEARCH				
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